

MITSUBISHI <DIGITAL ASSP>
M74HC533-1P/FP

OCTAL 3-STATE INVERTING D-TYPE TRANSPARENT LATCH

DESCRIPTION

The M74HC533-1 is an integrated circuit chip consisting of eight 3-state output D-type latches with common-enable input and output-enable input.

FEATURES

- High-fanout 3-state output : ($I_{OL}=24\text{mA}$, $I_{OH}=-24\text{mA}$)
- High-speed : 10ns typ. ($C_L=50\text{pF}$, $V_{CC}=5\text{V}$)
- Low power dissipation : $25\mu\text{W}/\text{package}$, max ($V_{CC}=5\text{V}$, $T_a=25^\circ\text{C}$, quiescent state)
- High noise margin : 30% of V_{CC} , min ($V_{CC}=4.5, 6\text{V}$)
- Capable of driving 60 74LSTTL loads
- Wide operating voltage range : $V_{CC}=2\sim 6\text{V}$
- Wide operating temperature range : $T_a=-40\sim +85^\circ\text{C}$

APPLICATION

General purpose, for use in industrial and consumer digital equipment.

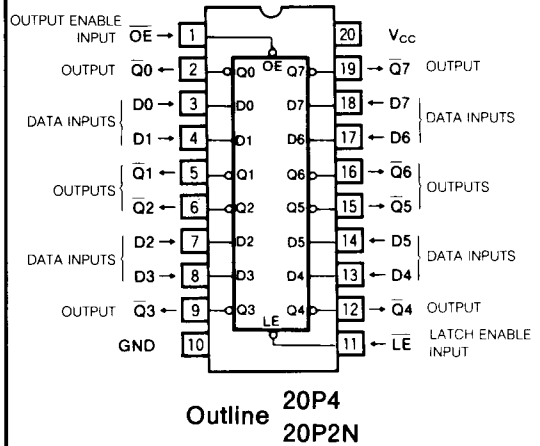
FUNCTION

Use of silicon gate technology allows the M74HC533-1 to maintain the low power dissipation and high noise margin characteristics of the standard CMOS logic 4000B series while giving high-speed performance equivalent to the 74LS533. The circuit is designed to suppress the increased switching noise that normally occurs at high output currents. The M74HC533-1 consists of eight D-type latches with latch-enable input $\overline{\text{LE}}$ and output-enable input $\overline{\text{OE}}$ common to all circuits.

When $\overline{\text{LE}}$ is high-level, the data input D appears at output $\overline{\text{Q}}$ through the latch and the $\overline{\text{Q}}$ state follows changes in the D state. When $\overline{\text{LE}}$ changes from high-level to low-level, the data existing immediately prior to the change at D will be stored in the latch.

Even if other inputs are changed when $\overline{\text{LE}}$ is low-level, the contents stored in the latch will not be affected.

PIN CONFIGURATION (TOP VIEW)



When $\overline{\text{OE}}$ is high-level, all outputs $\overline{\text{Q}}$ will become high-impedance state.

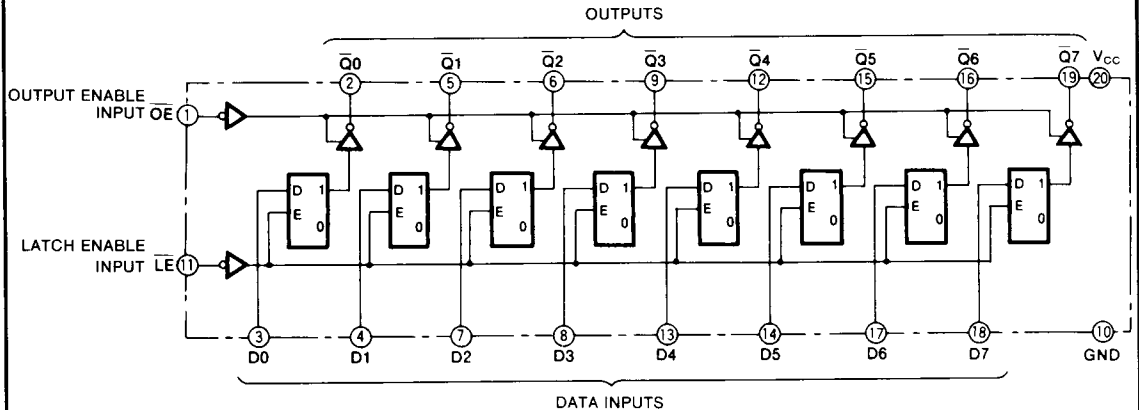
A version of the M74HC533-1 with the same pin connection and a noninverted output, the M74HC373-1, is also available.

FUNCTION TABLE (Note 1)

Inputs		Output	
$\overline{\text{OE}}$	$\overline{\text{LE}}$	D	$\overline{\text{Q}}$
L	H	H	L
L	H	L	H
L	L	X	$\overline{\text{Q}}^0$
H	X	X	Z

Note 1 : $\overline{\text{Q}}^0$: Output state $\overline{\text{Q}}$ before $\overline{\text{LE}}$ changed.
 Z : High impedance
 X : Irrelevant

LOGICAL DIAGRAM



OCTAL 3-STATE INVERTING D-TYPE TRANSPARENT LATCH

ABSOLUTE MAXIMUM RATINGS ($T_a = -40 \sim +85^\circ\text{C}$, unless otherwise noted)

Symbol	Parameter	Conditions	Ratings	Unit
V_{CC}	Supply voltage		$-0.5 \sim +7.0$	V
V_I	Input voltage		$-0.5 \sim V_{CC} + 0.5$	V
V_O	Output voltage		$-0.5 \sim V_{CC} + 0.5$	V
I_{IK}	Input protection diode current	$V_I < 0V$	-20	mA
		$V_I > V_{CC}$	20	
I_{OK}	Output parasitic diode current	$V_O < 0V$	-20	mA
		$V_O > V_{CC}$	20	
I_O	Output current		± 50	mA
I_{CC}	Supply/GND current	V_{CC}, GND	± 200	mA
P_d	Power dissipation	(Note 2)	500	mW
T_{stg}	Storage temperature		$-65 \sim +150$	$^\circ\text{C}$

Note 2 : M74HC533-1FP; $T_a = -40 \sim +75^\circ\text{C}$ and $T_a = 75 \sim 85^\circ\text{C}$ are derated at $-7\text{mW}/^\circ\text{C}$

RECOMMENDED OPERATING CONDITIONS ($T_a = -40 \sim +85^\circ\text{C}$)

Symbol	Parameter	Limits			Unit
		Min	Typ	Max	
V_{CC}	Supply voltage	2		6	V
V_I	Input voltage	0		V_{CC}	V
V_O	Output voltage	0		V_{CC}	V
T_{opr}	Operating temperature	-40		+85	$^\circ\text{C}$
t_r, t_f	Input rise time, fall time	$V_{CC} = 2.0V$		500	ns/V
		$V_{CC} = 4.5V$		50	
		$V_{CC} = 6.0V$		30	

ELECTRICAL CHARACTERISTICS

Symbol	Parameter	Test conditions	Limits					Unit	
			$V_{CC}(V)$	25 $^\circ\text{C}$			$-40 \sim +85^\circ\text{C}$		
				Min	Typ	Max	Min		Max
V_{IH}	High-level input voltage	$V_O = 0.1V, V_{CC} = 0.1V$ $ I_O = 20\mu A$	2.0	1.5			1.5	V	
			4.5	3.15			3.15		
			6.0	4.2			4.2		
V_{IL}	Low-level input voltage	$V_O = 0.1V, V_{CC} = 0.1V$ $ I_O = 20\mu A$	2.0			0.5	0.5	V	
			4.5			1.35	1.35		
			6.0			1.8	1.8		
V_{OH}	High-level output voltage	$V_I = V_{IL}, V_{IH}$	$I_{OH} = -20\mu A$	2.0	1.9		1.9	V	
			$I_{OH} = -20\mu A$	4.5	4.4		4.4		
			$I_{OH} = -20\mu A$	6.0	5.9		5.9		
			$I_{OH} = -24mA$	4.5	3.83		3.70		
V_{OL}	Low-level output voltage	$V_I = V_{IH}, V_{IL}$	$I_{OL} = 20\mu A$	2.0		0.1	0.1	V	
			$I_{OL} = 20\mu A$	4.5		0.1	0.1		
			$I_{OL} = 20\mu A$	6.0		0.1	0.1		
			$I_{OL} = 24mA$	4.5		0.44	0.53		
I_{IH}	High-level input current	$V_I = 6V$	6.0			0.1	μA		
I_{IL}	Low-level input current	$V_I = 0V$	6.0			-0.1	-1.0	μA	
I_{OZH}	Off-state high-level output current	$V_I = V_{IH}, V_{IL}, V_O = V_{CC}$	6.0			0.5	5.0	μA	
I_{OZL}	Off-state low-level output current	$V_I = V_{IH}, V_{IL}, V_O = GND$	6.0			-0.5	-5.0	μA	
I_{CC}	Quiescent supply current	$V_I = V_{CC}, GND, I_O = 0\mu A$	6.0			5.0	50.0	μA	

OCTAL 3-STATE INVERTING D-TYPE TRANSPARENT LATCH

SWITCHING CHARACTERISTICS (V_{CC} = 5V, T_a = 25°C)

Symbol	Parameter	Test conditions	Limits			Unit
			Min	Typ	Max	
t _{TLH}	Low-to high-level and high-to low-level output transition time	C _L = 50pF (Note 4)			10	ns
t _{THL}					10	ns
t _{PLH}	Low-to high-level and high-to low-level output propagation time (D - Q̄)				18	ns
t _{PHL}					18	ns
t _{PLH}	Low-to high-level and high-to low-level output propagation time (LĒ - Q̄)				20	ns
t _{PHL}					20	ns
t _{PLZ}	Low-level and high-level output disable time (OE - Q̄)	C _L = 5 pF (Note 4)			18	ns
t _{PHZ}					18	ns
t _{PZL}	Low-level and high-level output enable time (OE - Q̄)	C _L = 50pF (Note 4)			20	ns
t _{PZH}					20	ns

SWITCHING CHARACTERISTICS (V_{CC} = 2~6V, T_a = -40~+85°C)

Symbol	Parameter	Test conditions	Limits						Unit				
			V _{CC} (V)	25°C			-40~+85°C						
				Min	Typ	Max	Min	Max					
t _{TLH}	Low-to high-level and high-to low-level output transition time	C _L = 50pF (Note 4)	2.0		12	60		75	ns				
			4.5		5	12		15					
			6.0		4	10		13					
t _{THL}			Low-to high-level and high-to low-level output transition time	C _L = 50pF (Note 4)	2.0		16	60		75	ns		
					4.5		5	12		15			
					6.0		4	10		13			
t _{PLH}					Low-to high-level and high-to low-level output propagation time (D - Q̄)	C _L = 50pF (Note 4)	2.0		30	95		120	ns
							4.5		11	19		24	
							6.0		9	16		20	
t _{PHL}	Low-to high-level and high-to low-level output propagation time (D - Q̄)	C _L = 50pF (Note 4)					2.0		30	95		120	ns
							4.5		11	19		24	
							6.0		9	16		20	
t _{PLH}			Low-to high-level and high-to low-level output propagation time (LĒ - Q̄)	C _L = 50pF (Note 4)			2.0		33	105		130	ns
							4.5		12	21		26	
							6.0		9	18		22	
t _{PHL}					Low-to high-level and high-to low-level output propagation time (LĒ - Q̄)	C _L = 50pF (Note 4)	2.0		33	105		130	ns
							4.5		12	21		26	
							6.0		10	18		22	
t _{PLZ}	Low-level and high-level output disable time (OE - Q̄)	C _L = 50pF (Note 4)					2.0		15	105		130	ns
							4.5		7	21		26	
							6.0		6	18		22	
t _{PHZ}			Low-level and high-level output disable time (OE - Q̄)	C _L = 50pF (Note 4)			2.0		18	105		130	ns
							4.5		11	21		26	
							6.0		8	18		22	
t _{PZL}					Low-level and high-level output enable time (OE - Q̄)	C _L = 50pF (Note 4)	2.0		22	105		130	ns
							4.5		9	21		26	
							6.0		7	18		22	
t _{PZH}	Low-level and high-level output enable time (OE - Q̄)	C _L = 50pF (Note 4)					2.0		25	105		130	ns
							4.5		10	21		26	
							6.0		9	18		22	
C _I			Input capacitance						10		10	pF	
C _O			Off-state output capacitance	OE = V _{CC}					15		15	pF	
C _{PD}			Power dissipation capacitance (Note 3)					45.9				pF	

Note 3 : C_{PD} is the internal capacitance of the IC calculated from operation supply current under no-load conditions (per latch). The power dissipated during operation under no-load condition is calculated using the following formula :

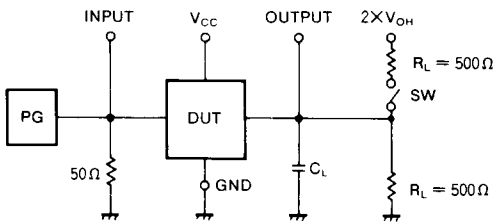
$$P_b = C_{PD} \cdot V_{CC}^2 \cdot f_i + I_{CC} \cdot V_{CC}$$

OCTAL 3-STATE INVERTING D-TYPE TRANSPARENT LATCH

TIMING REQUIREMENTS ($V_{CC} = 2\sim 6V$, $T_a = -40\sim +85^\circ C$)

Symbol	Parameter	Test conditions	Limits						Unit
			25°C			-40~+85°C			
			$V_{CC}(V)$	Min	Typ	Max	Min		
t_w	Latch-enable pulse width		2.0	60	7		75		ns
			4.5	12	2		15		
			6.0	10	2		13		
t_{su}	D setup time with respect to \overline{LE}		2.0	50	3		65		ns
			4.5	10	1		13		
			6.0	9	1		11		
t_h	D hold time with respect to \overline{LE}		2.0	25	-2		30		ns
			4.5	5	0		6		
			6.0	5	0		6		

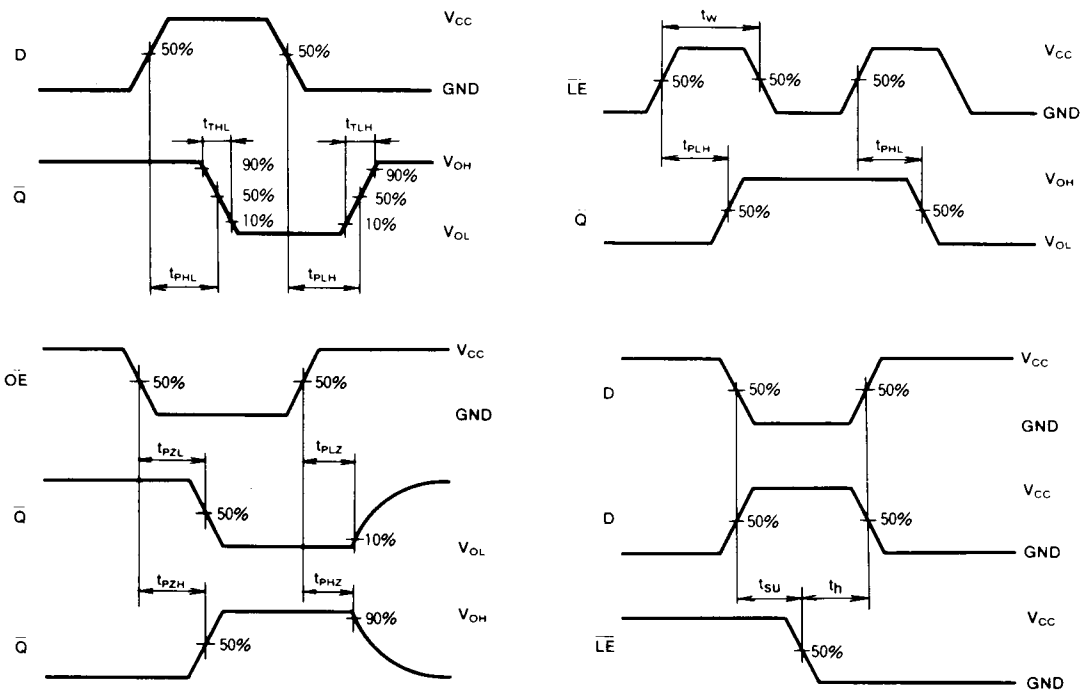
Note 4 : Test Circuit



Parameter	SW
t_{TLH} , t_{THL}	Open
t_{PLH} , t_{PHL}	Open
t_{PLZ}	Closed
t_{PHZ}	Open
t_{PZL}	Closed
t_{PZH}	Open

- (1) The pulse generator (PG) has the following characteristics (10%~90%) : $t_r=3ns$, $t_f=3ns$
- (2) The capacitance C_L includes stray wiring capacitance and the probe input capacitance.

TIMING DIAGRAM



MITSUBISHI HIGH SPEED CMOS
PACKAGE OUTLINES

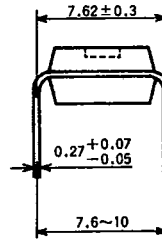
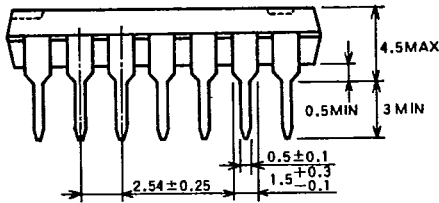
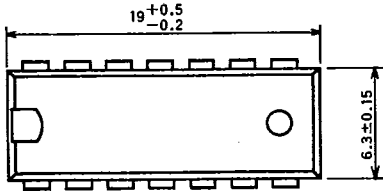
6249827 MITSUBISHI (DGTL LOGIC)

91D 12849

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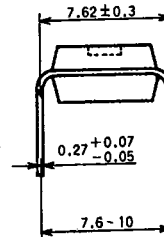
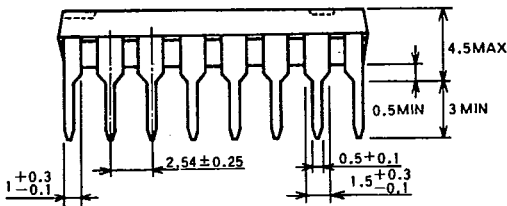
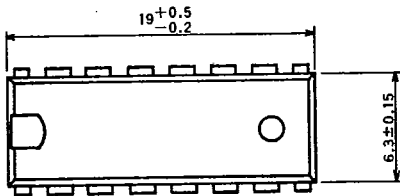
TYPE 14P4 14-PIN MOLDED PLASTIC DIP

Dimension in mm



TYPE 16P4 16-PIN MOLDED PLASTIC DIP

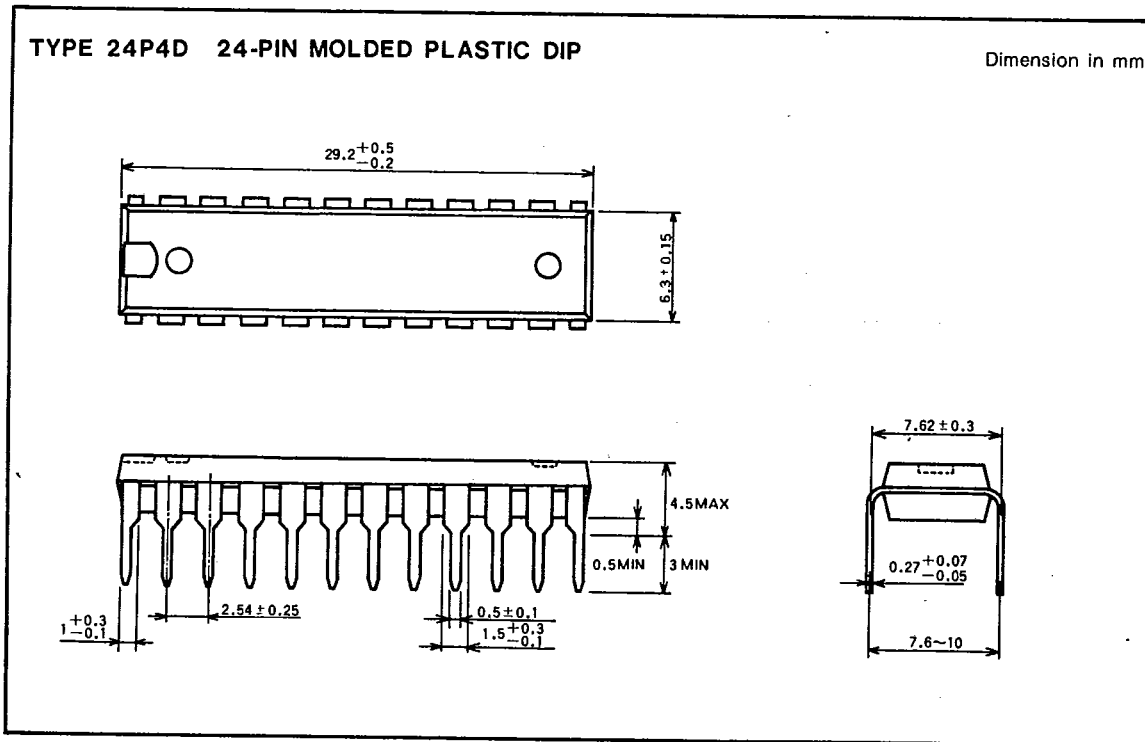
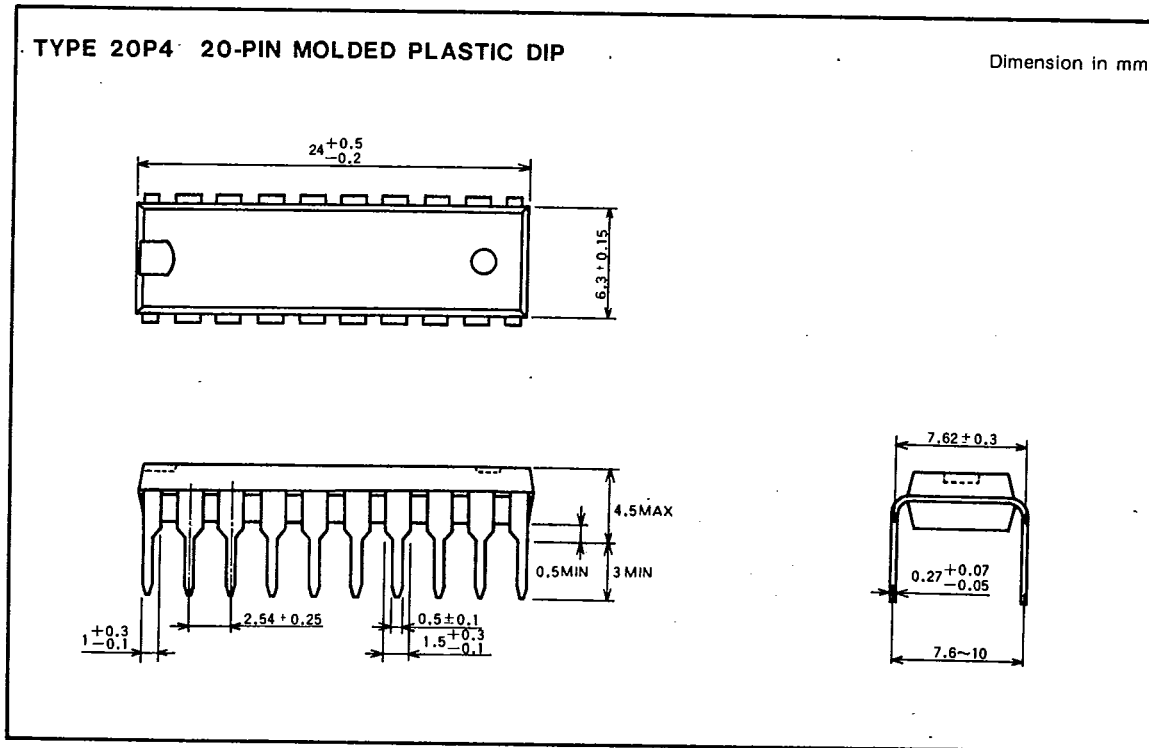
Dimension in mm



MITSUBISHI HIGH SPEED CMOS
PACKAGE OUTLINES

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91D 12850 D.T-90-20



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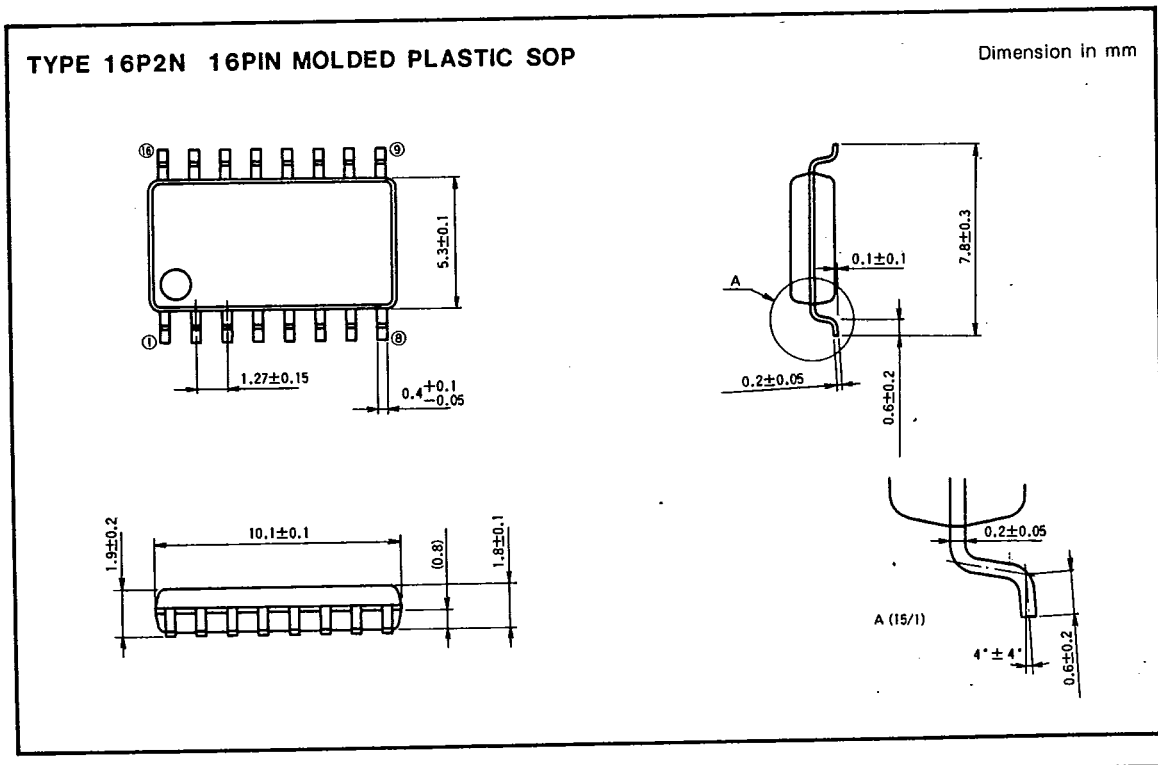
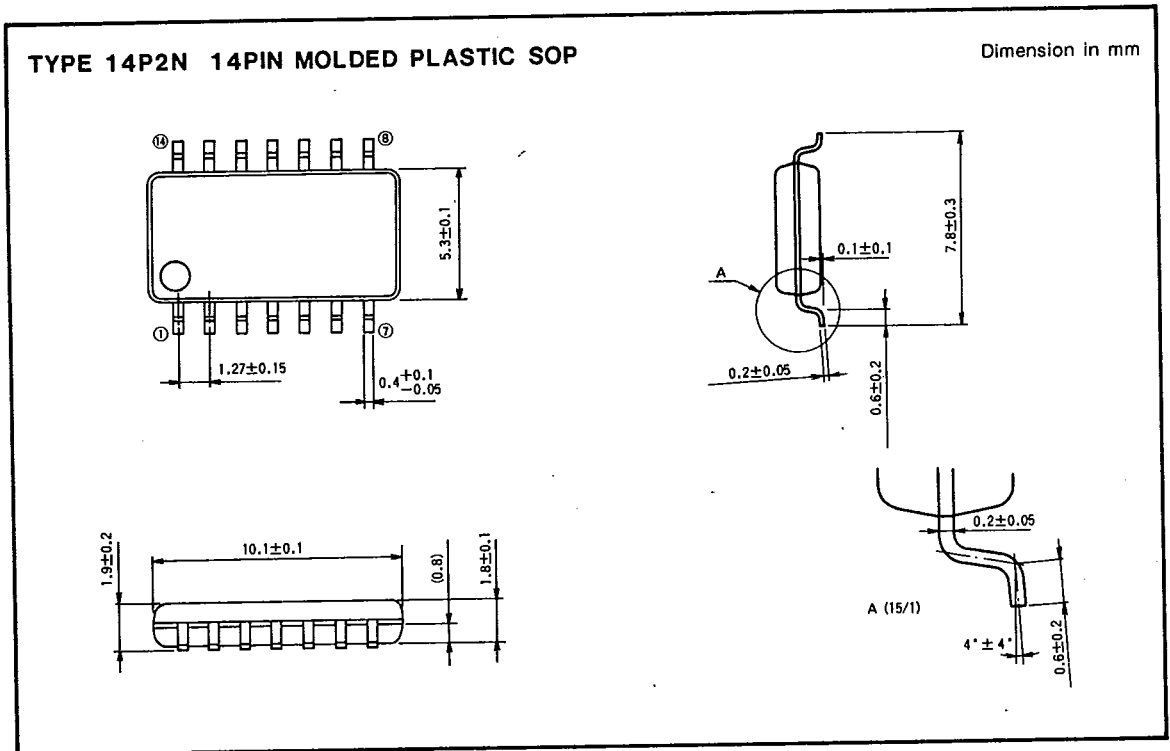


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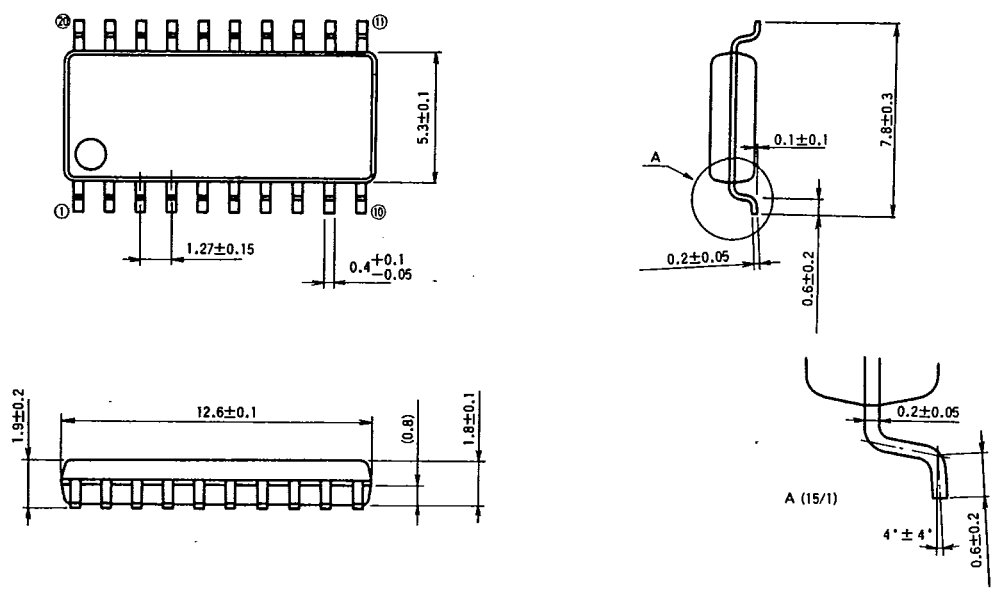
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91D 12851 D T-90.20



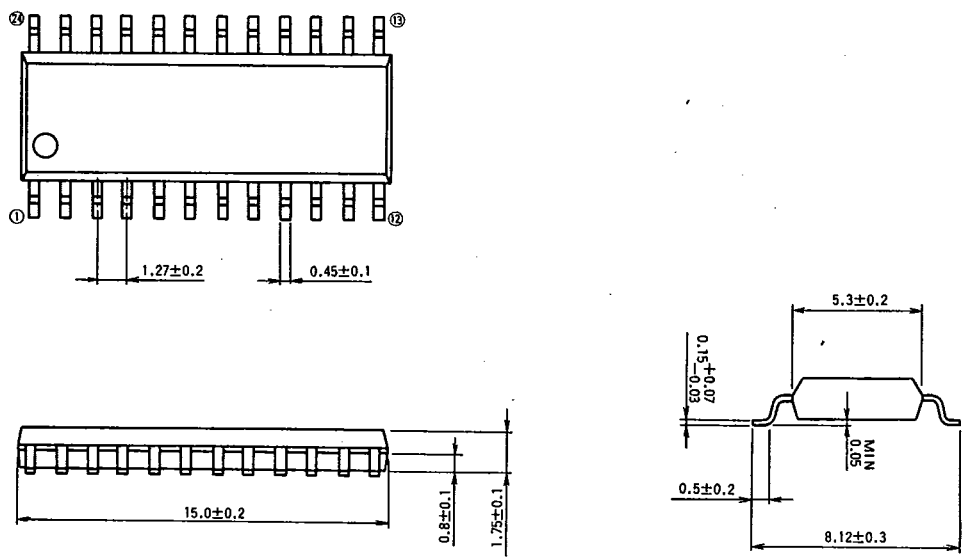
TYPE 20P2N 20PIN MOLDED PLASTIC SOP

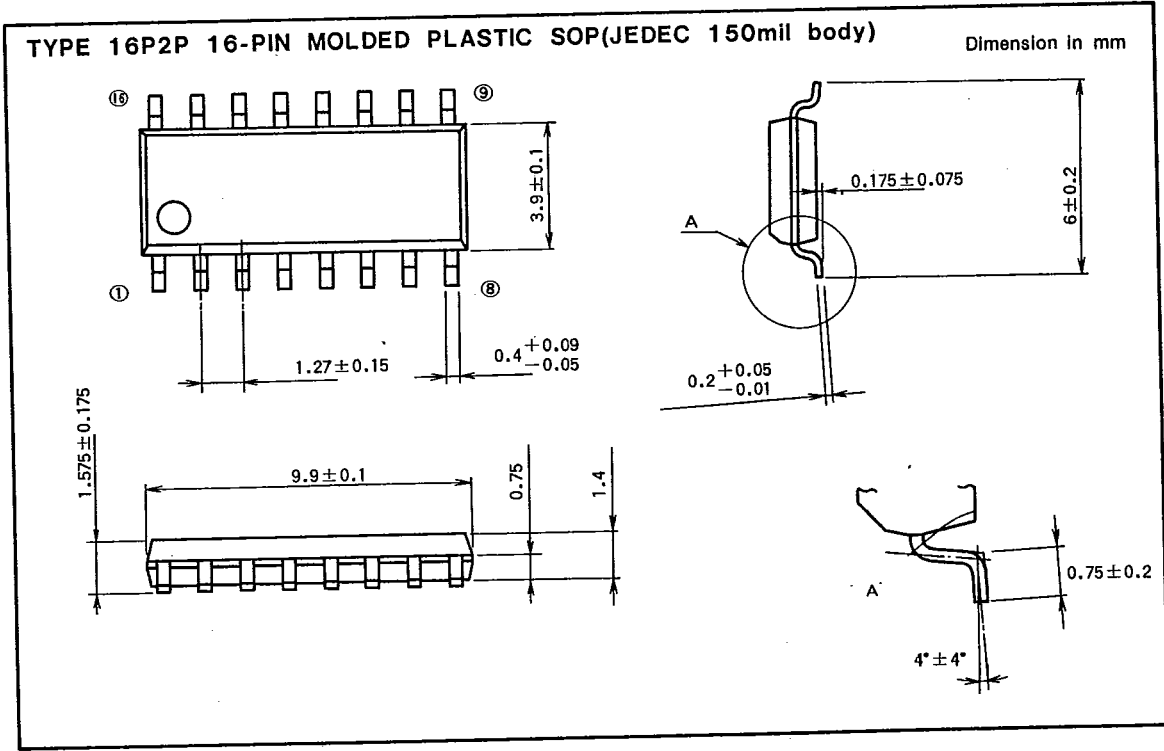
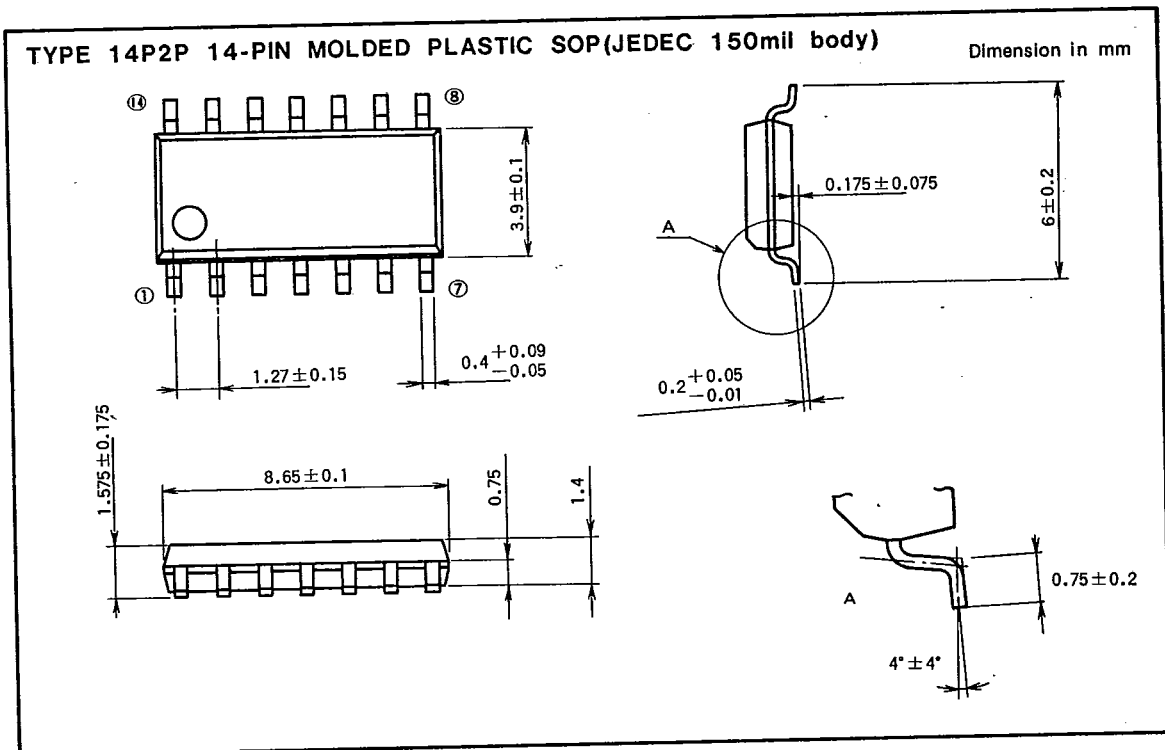
Dimension in mm



TYPE 24P2 24PIN MOLDED PLASTIC SOP

Dimension in mm





MITSUBISHI HIGH SPEED CMOS
PACKAGE OUTLINES

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91D 12854 D T-90-20

